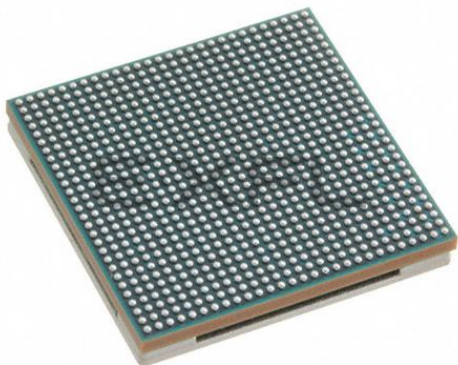




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	300000
Total RAM Bits	21094400
Number of I/O	388
Number of Gates	-
Voltage - Supply	0.97V ~ 1.08V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/mpf300t-fcg784e

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3 References

The following documents are recommended references. For more information about PolarFire static and dynamic power data, see the [PolarFire Power Estimator Spreadsheet](#).

- [PO0137](#): PolarFire FPGA Product Overview
- [ER0217](#): PolarFire FPGA Pre-Production Device Errata
- [UG0722](#): PolarFire FPGA Packaging and Pin Descriptions Users Guide
- [UG0726](#): PolarFire FPGA Board Design User Guide
- [UG0686](#): PolarFire FPGA User I/O User Guide
- [UG0680](#): PolarFire FPGA Fabric User Guide
- [UG0714](#): PolarFire FPGA Programming User Guide
- [UG0684](#): PolarFire FPGA Clocking Resources User Guide
- [UG0687](#): PolarFire FPGA 1G Ethernet Solutions User Guide
- [UG0727](#): PolarFire FPGA 10G Ethernet Solutions User Guide
- [UG0748](#): PolarFire FPGA Low Power User Guide
- [UG0676](#): PolarFire FPGA DDR Memory Controller User Guide
- [UG0743](#): PolarFire FPGA Debugging User Guide
- [UG0725](#): PolarFire FPGA Device Power-Up and Resets User Guide
- [UG0677](#): PolarFire FPGA Transceiver User Guide
- [UG0685](#): PolarFire FPGA PCI Express User Guide
- [UG0753](#): PolarFire FPGA Security User Guide
- [UG0752](#): PolarFire FPGA Power Estimator User Guide

Table 8 • Maximum Overshoot During Transitions for GPIO

AC (V _{IN}) Overshoot Duration as % at T _J = 100 °C	Condition (V)
100	3.8
100	3.85
100	3.9
100	3.95
70	4
50	4.05
33	4.1
22	4.15
14	4.2
9.8	4.25
6.5	4.3
4.4	4.35
3	4.4
2	4.45
1.4	4.5
0.9	4.55
0.6	4.6

Note: Overshoot level is for V_{DDI} at 3.3 V.

The following table shows the maximum AC input voltage (V_{IN}) undershoot duration for GPIO.

Table 9 • Maximum Undershoot During Transitions for GPIO

AC (V _{IN}) Undershoot Duration as % at T _J = 100 °C	Condition (V)
100	-0.5
100	-0.55
100	-0.6
100	-0.65
100	-0.7
100	-0.75
100	-0.8
100	-0.85
100	-0.9
100	-0.95
100	-1
100	-1.05
100	-1.1
100	-1.15
100	-1.2
69	-1.25
45	-1.3

I/O Standard	V _{DDI} Min (V)	V _{DDI} Typ (V)	V _{DDI} Max (V)	V _{IL} Min (V)	V _{IL} Max (V)	V _{IH} Min (V)	V _{IH} ¹ Max (V)
SSTL135I	1.283	1.35	1.418	-0.3	V _{REF} - 0.09	V _{REF} + 0.09	1.418
SSTL135II	1.283	1.35	1.418	-0.3	V _{REF} - 0.09	V _{REF} + 0.09	1.418
HSTL15I	1.425	1.5	1.575	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	1.575
HSTL15II	1.425	1.5	1.575	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	1.575
HSTL135I	1.283	1.35	1.418	-0.3	V _{REF} - 0.09	V _{REF} + 0.09	1.418
HSTL135II	1.283	1.35	1.418	-0.3	V _{REF} - 0.09	V _{REF} + 0.09	1.418
HSTL12I	1.14	1.2	1.26	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	1.26
HSTL12II	1.14	1.2	1.26	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	1.26
HSUL18I	1.71	1.8	1.89	-0.3	0.3 x V _{DDI}	0.7 x V _{DDI}	1.89
HSUL18II	1.71	1.8	1.89	-0.3	0.3 x V _{DDI}	0.7 x V _{DDI}	1.89
HSUL12I	1.14	1.2	1.26	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	1.26
POD12I	1.14	1.2	1.26	-0.3	V _{REF} - 0.08	V _{REF} + 0.08	1.26
POD12II	1.14	1.2	1.26	-0.3	V _{REF} - 0.08	V _{REF} + 0.08	1.26

1. GPIO V_{IH} max is 3.45 V with PCI clamp diode turned off regardless of mode, that is, over-voltage tolerant.

2. For external stub-series resistance. This resistance is on-die for GPIO.

Note: 3.3 V and 2.5 V are only supported in GPIO banks.

I/O Standard	Bank Type	VICM_RANGE Libero Setting	V _{ICM} ^{1,3} Min (V)	V _{ICM} ^{1,3} Typ (V)	V _{ICM} ^{1,3} Max (V)	V _{ID} ² Min (V)	V _{ID} Typ (V)	V _{ID} Max (V)
HCSL25 ⁶	GPIO	Mid (default)	0.6	1.25	2.35	0.1	0.55	1.1
		Low	0.05	0.35	0.8	0.1	0.55	1.1
HCSL18 ⁵	HSIO	Mid (default)	0.6	1.0	1.65	0.1	0.55	1.1
		Low	0.05	0.4	0.8	0.1	0.55	1.1
BUSLVDSE25	GPIO	Mid (default)	0.6	1.25	2.35	0.05	0.1	V _{DDIn}
		Low	0.05	0.4	0.8	0.05	0.1	V _{DDIn}
MLVDSE25	GPIO	Mid (default)	0.6	1.25	2.35	0.05	0.35	2.4
		Low	0.05	0.4	0.8	0.05	0.35	2.4
LVPECL33	GPIO	Mid (default)	0.6	1.65	2.35	0.05	0.8	2.4
		Low	0.05	0.4	0.8	0.05	0.8	2.4
LVPECLE33	GPIO	Mid (default)	0.6	1.65	2.35	0.05	0.8	2.4
		Low	0.05	0.4	0.8	0.05	0.8	2.4
MIPI25	GPIO	Mid (default)	0.6	1.25	2.35	0.05	0.2	0.3
		Low	0.05	0.2	0.8	0.05	0.2	0.3

1. V_{ICM} is the input common mode.
2. V_{ID} is the input differential voltage.
3. V_{ICM} rules are as follows:
 - a. V_{ICM} must be less than V_{DDI} – 0.4 V;
 - b. V_{ICM} + V_{ID}/2 must be <V_{DDI} + 0.4 V;
 - c. V_{ICM} – V_{ID}/2 must be >VSS – 0.3 V;
 - d. Any differential input with V_{ICM} ≤ 0.6 V requires the low common mode setting in Libero (VICM_RANGE=LOW).
4. VDDI = 1.8 V, VDDAUX = 2.5 V.
5. HSIO receiver only.
6. GPIO receiver only.

Table 15 • Differential DC Output Levels

I/O Standard	Bank Type	V _{OCM} ¹ Min (V)	V _{OCM} Typ (V)	V _{OCM} Max (V)	V _{OD} ² Min (V)	V _{OD} ² Typ (V)	V _{OD} ² Max (V)
LVDS33	GPIO		1.2		0.25	0.35	0.45
LVDS25	GPIO		1.2		0.25	0.35	0.45
LCMDS33	GPIO		0.6		0.25	0.35	0.45
LCMDS25	GPIO		0.6		0.25	0.35	0.45
RSDS33	GPIO		1.2		0.17	0.2	0.23
RSDS25	GPIO		1.2		0.17	0.2	0.23
MINILVDS33	GPIO		1.2		0.3	0.4	0.6
MINILVDS25	GPIO		1.2		0.3	0.4	0.6
SUBLVDS33	GPIO		0.9		0.1	0.15	0.3
SUBLVDS25	GPIO		0.9		0.1	0.15	0.3
PPDS33	GPIO		0.8		0.17	0.2	0.23
PPDS25	GPIO		0.8		0.17	0.2	0.23
SLVSE15 ³	GPIO, HSIO		0.2		0.12	0.135	0.15
BUSLVDSE25 ³	GPIO		1.25		0.24	0.262	0.272

I/O Standard	Bank Type	V _{OCM} ¹ Min (V)	V _{OCM} Typ (V)	V _{OCM} Max (V)	V _{OD} ² Min (V)	V _{OD} ² Typ (V)	V _{OD} ² Max (V)
MLVDSSE25 ³	GPIO		1.25		0.396	0.442	0.453
LVPECL33 ³	GPIO		1.65		0.664	0.722	0.755
MIPIE25 ³	GPIO		0.25		0.1	0.22	0.3

1. V_{OCM} is the output common mode voltage.
2. V_{OD} is the output differential voltage.
3. Emulated output only.

6.3.3 Complementary Differential DC Input and Output Levels

The following tables list the complementary differential DC I/O levels.

Table 16 • Complementary Differential DC Input Levels

I/O Standard	V _{DDI} Min (V)	V _{DDI} Typ (V)	V _{DDI} Max (V)	V _{ICM} ^{1,3} Min (V)	V _{ICM} ^{1,3} Typ (V)	V _{ICM} ^{1,3} Max (V)	V _{ID} ² Min (V)	V _{ID} Max (V)
SSTL25I	2.375	2.5	2.625	1.164	1.250	1.339	0.1	
SSTL25II	2.375	2.5	2.625	1.164	1.250	1.339	0.1	
SSTL18I	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
SSTL18II	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
SSTL15I	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
SSTL15II	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
SSTL135I	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
SSTL135II	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
HSTL15I	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
HSTL15II	1.425	1.5	1.575	0.698	0.750	0.803	0.1	
HSTL135I	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
HSTL135II	1.283	1.35	1.418	0.629	0.675	0.723	0.1	
HSTL12I	1.14	1.2	1.26	0.559	0.600	0.643	0.1	
HSUL18I	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
HSUL18II	1.71	1.8	1.89	0.838	0.900	0.964	0.1	
HSUL12I	1.14	1.2	1.26	0.559	0.600	0.643	0.1	
POD12I	1.14	1.2	1.26	0.787	0.840	0.895	0.1	
POD12II	1.14	1.2	1.26	0.787	0.840	0.895	0.1	

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage.
3. V_{ICM} rules are as follows:
 - a. V_{ICM} must be less than V_{DDI} - 0.4V;
 - b. V_{ICM} + V_{ID}/2 must be < V_{DDI} + 0.4 V;
 - c. V_{ICM} - V_{ID}/2 must be > V_{SS} - 0.3 V.

Standard	Description	V_L^1	V_H^1	V_{ID}^2	V_{ICM}^2	$V_{MEAS}^{3,4}$	$V_{REF}^{1,5}$	Unit
SLVS25	SLVS 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.200	0		V
SLVS18	SLVS 1.8 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.200	0		V
HCSL33	High-speed current steering logic (HCSL) 3.3 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.350	0		V
HCSL25	HCSL 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.350	0		V
HCSL18	HCSL 1.8 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.350	0		V
BLVDSE25 ⁶	Bus LVDS 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
MLVDSE25 ⁶	Multipoint LVDS 2.5 V	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
LVPECL33	Low-voltage positive emitter coupled logic	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.650	0		V
LVPECL33 ⁶	Low-voltage positive emitter coupled logic	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.650	0		V
SSTL25I	Differential SSTL 2.5 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
SSTL25II	Differential SSTL 2.5 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	1.250	0		V
SSTL18I	Differential SSTL 1.8 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.900	0		V
SSTL18II	Differential SSTL 1.8 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.900	0		V
SSTL15	Differential SSTL 1.5 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
SSTL135	Differential SSTL 1.5 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
HSTL15I	Differential HSTL 1.5 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
HSTL15II	Differential HSTL 1.5 V Class II	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.750	0		V
HSTL135I	Differential HSTL 1.35 V Class I	$V_{ICM} - .125$	$V_{ICM} + .125$	0.250	0.675	0		V

7.1.6 User I/O Switching Characteristics

The following section describes characteristics for user I/O switching.

For more information about user I/O timing, see the *PolarFire I/O Timing Spreadsheet* (to be released).

7.1.6.1 I/O Digital

The following tables provide information about I/O digital.

Table 30 • I/O Digital Receive Single-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Clock-to-Data Condition
F _{MAX}	RX_SDR_G_A	Rx SDR							MHz	From a global clock source, aligned
F _{MAX}	RX_SDR_L_A	Rx SDR							MHz	From a lane clock source, aligned
F _{MAX}	RX_SDR_G_C	Rx SDR							MHz	From a global clock source, centered
F _{MAX}	RX_SDR_L_C	Rx SDR							MHz	From a lane clock source, centered

Table 31 • I/O Digital Receive Double-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Clock-to-Data Condition
F _{MAX}	RX_DDR_G_A	Rx DDR		335			335	MHz	MHz	From a global clock source, aligned
F _{MAX}	RX_DDR_L_A	Rx DDR		250			250		MHz	From a lane clock source, aligned
F _{MAX}	RX_DDR_G_C	Rx DDR		335			335		MHz	From a global clock source, centered
F _{MAX}	RX_DDR_L_C	Rx DDR		250			250		MHz	From a lane clock source, centered
F _{MAX} 2:1	RX_DDRX_B_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	-1 Min	-1 Typ	-1 Max	Unit	Clock-to-Data Condition
F _{MAX} 4:1	RX_DDRX_B_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
F _{MAX} 8:1	RX_DDRX_B_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
F _{MAX} 2:1	RX_DDRX_B_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered
F _{MAX} 4:1	RX_DDRX_B_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered
F _{MAX} 8:1	RX_DDRX_B_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered
F _{MAX} 2:1	RX_DDRX_BL_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
F _{MAX} 4:1	RX_DDRX_BL_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
F _{MAX} 8:1	RX_DDRX_BL_A	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
F _{MAX} 2:1	RX_DDRX_BL_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered
F _{MAX} 4:1	RX_DDRX_BL_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Clock-to-Data Condition
F _{MAX} 8:1	RX_DDRX_BL_C	Rx DDR digital mode							MHz	From a HS_IO_CLK clock source, centered

Table 32 • I/O Digital Transmit Single-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Forwarded Clock-to-Data Skew
Output F _{MAX}	TX_SDR_G_A	Tx SDR							MHz	From a global clock source, aligned ¹
	TX_SDR_G_C	Tx SDR							MHz	From a global clock source, centered ¹

1. A centered clock-to-data interface can be created with a negedge launch of the data.

Table 33 • I/O Digital Transmit Double-Data Rate Switching Characteristics

Parameter	Interface Name	Topology	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit	Forwarded Clock-to-Data Skew
Output F _{MAX}	TX_DDR_G_A	Tx DDR			335			335	MHz	From a global clock source, aligned
	TX_DDR_G_C	Tx DDR			335			335	MHz	From a global clock source, centered
	TX_DDR_L_A	Tx DDR			250			250	MHz	From a lane clock source, aligned
	TX_DDR_L_C	Tx DDR			250			250	MHz	From a lane clock source, centered
Output F _{MAX} 2:1	TX_DDRX_B_A	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
Output F _{MAX} 4:1	TX_DDRX_B_A	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned
Output F _{MAX} 8:1	TX_DDRX_B_A	Tx DDR digital mode							MHz	From a HS_IO_CLK clock source, aligned

Parameter	Symbol	V _{DD} = 1.0 V STD	V _{DD} = 1.0 V –1	V _{DD} = 1.05 V STD	V _{DD} = 1.05 V –1	Unit	Condition
Regional clock duty cycle distortion	T _{DCDR}	120	120	120	120	ps	At 250 MHz

The following table provides clocking specifications from –40 °C to 100 °C.

Table 36 • High-Speed I/O Clock Characteristics (–40 °C to 100 °C)

Parameter	Symbol	V _{DD} = 1.0 V STD	V _{DD} = 1.0 V –1	V _{DD} = 1.05 V STD	V _{DD} = 1.05 V –1	Unit	Condition
High-speed I/O clock F _{MAX}	F _{MAXB}	1000	1250	1000	1250	MHz	HSIO and GPIO
High-speed I/O clock skew ¹	F _{SKEWB}	30	20	30	20	ps	HSIO without bridging
	F _{SKEWB}	600	500	600	500	ps	HSIO with bridging
	F _{SKEWB}	45	35	45	35	ps	GPIO without bridging
	F _{SKEWB}	75	60	75	60	ps	GPIO with bridging
High-speed I/O clock duty cycle distortion ²	T _{DCB}	90	90	90	90	ps	HSIO without bridging
	T _{DCB}	115	115	115	115	ps	HSIO with bridging
	T _{DCB}	90	90	90	90	ps	GPIO without bridging
	T _{DCB}	115	115	115	115	ps	GPIO with bridging

1. F_{SKEWB} is the worst-case clock-tree skew observable between sequential I/O elements. Clock-tree skew is significantly smaller at I/O registers close to each other and fed by the same or adjacent clock-tree branches. Use the Microsemi Timing Analyzer tool to evaluate clock skew specific to the design.
2. Parameters listed in this table correspond to the worst-case duty cycle distortion observable at the I/O flip flops. IBIS should be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times for any I/O standard.

7.2.2

PLL

The following table provides information about PLL.

Table 37 • PLL Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit
Input clock frequency (integer mode)	F _{INI}	1		1250	MHz
Input clock frequency (fractional mode)	F _{INF}	10		1250	MHz
Minimum reference or feedback pulse width ¹	F _{INPULSE}	200			ps
Frequency at the Frequency Phase Detector (PFD) (integer mode)	F _{PHDET1}	1		312	MHz
Frequency at the PFD (fractional mode)	F _{PHDET2}	10	50	125	MHz
Allowable input duty cycle	F _{INDUTY}	25		75	%

Parameter	Symbol	STD Min	STD Typ	STD Max	–1 Min	–1 Typ	–1 Max	Unit
Reference clock input rate ^{1, 2, 3}	F _{XCVRREFCLKMAX} CASCADE	20		156	20		156	MHz
Reference clock rate at the PFD ⁴	F _{TXREFCLKPFD}	20		156	20		156	MHz
Reference clock rate recommended at the PFD for Tx rates 10 Gbps and above ⁴	F _{TXREFCLKPFD10G}	75		156	75		156	MHz
Tx reference clock phase noise requirements to meet jitter specifications (156 MHz clock at reference clock input) ⁵	F _{TXREFPN}			–110			–110	dBc /Hz
Phase noise at 10 KHz	F _{TXREFPN}			–110			–110	dBc /Hz
Phase noise at 100 KHz	F _{TXREFPN}			–115			–115	dBc /Hz
Phase noise at 1 MHz	F _{TXREFPN}			–135			–135	dBc /Hz
Reference clock input rise time (10%–90%)	T _{REFRISE}		200	500		200	500	ps
Reference clock input fall time (90%–10%)	T _{REFFALL}		200	500		200	500	ps
Reference clock duty cycle	T _{REFDUTY}	40		60	40		60	%
Spread spectrum modulation spread ⁶	Mod_Spread	0.1		3.1	0.1		3.1	%
Spread spectrum modulation frequency ⁷	Mod_Freq	TxREF CLKPFD/ (128)	32	TxREF CLKPFD/ (128*63)	TxREF CLKPFD/ (128)	32	TxREF CLKPFD/ (128*63)	KHz

1. See the maximum reference clock rate allowed per input buffer standard.
2. The minimum value applies to this clock when used as an XCVR reference clock. It does not apply when used as a non-XCVR input buffer (DC input allowed).
3. Cascaded reference clock.
4. After reference clock input divider.
5. Required maximum phase noise is scaled based on actual F_{TxRefClkPFD} value by $20 \times \log_{10} (\text{TxRefClkPFD} / 156 \text{ MHz})$. It is assumed that the reference clock divider of 4 is used for these calculations to always meet the maximum PFD frequency specification.
6. Programmable capability for depth of down-spread or center-spread modulation.
7. Programmable modulation rate based on the modulation divider setting (1 to 63).

7.4.3 Transceiver Reference Clock I/O Standards

The following table describes the differential I/O standards supported as transceiver reference clocks.

5. Improved jitter characteristics for a specific industry standard are possible in many cases due to improved reference clock or higher V_{CO} rate used.
6. Tx jitter is specified with all transmitters on the device enabled, a 10–12-bit error rate (BER) and Tx data pattern of PRBS7.
7. From the PMA mode, the TX_ELEC_IDLE port to the XVCR TXP/N pins.
FTxRefClk = 75 MHz with typical settings.
For data rates greater than 10.3125 Gbps, VDDA must be set to 1.05 V mode. See supply tolerance in the section [Recommended Operating Conditions](#) (see page 6). (see page 6)

7.4.6 Receiver Performance

The following table describes performance of the receiver.

Table 53 • PolarFire Transceiver Receiver Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
Input voltage range	V_{IN}	0		$V_{DDA} + 0.3$	V	
Differential peak-to-peak amplitude	V_{IDPP}	140		1250	mV	
Differential termination	V_{ITERM}		85		Ω	
	V_{ITERM}		100		Ω	
	V_{ITERM}		150		Ω	
Common mode voltage	V_{ICMDC}^1	$0.7 \times V_{DDA}$		$0.9 \times V_{DDA}$	V	DC coupled
Exit electrical idle detection time	T_{EIDET}		50	100	ns	
Run length of consecutive identical digits (CID)	C_{ID}			200	UI	
CDR PPM tolerance ²	C_{DRPPM}			1.15	% UI	
CDR lock-to-data time	T_{LTD}				CDR_{REFCLK} UI	
CDR lock-to-ref time	T_{LTF}				CDR_{REFCLK} UI	
Loss-of-signal detect (Peak Detect Range setting = high) ⁹	$V_{DETLHIGH}$				mV	Setting = 1
	$V_{DETLHIGH}$				mV	Setting = 2
	$V_{DETLHIGH}$				mV	Setting = 3
	$V_{DETLHIGH}$				mV	Setting = 4
	$V_{DETLHIGH}$				mV	Setting = 5
	$V_{DETLHIGH}$				mV	Setting = 6
	$V_{DETLHIGH}$				mV	Setting = 7
Loss-of-signal detect (Peak Detect Range setting = low) ⁹	$V_{DETLLOW}$	65		175	mV	Setting = PCIe ^{3,7}
	$V_{DETLLOW}$	95		190	mV	Setting = SATA ^{4,8}
	$V_{DETLLOW}$	75		170	mV	Setting = 1
	$V_{DETLLOW}$	95		185	mV	Setting = 2
	$V_{DETLLOW}$	100		190	mV	Setting = 3
	$V_{DETLLOW}$	140		210	mV	Setting = 4
	$V_{DETLLOW}$	155		240	mV	Setting = 5
	$V_{DETLLOW}$	165		245	mV	Setting = 6
	$V_{DETLLOW}$	170		250	mV	Setting = 7
Sinusoidal jitter tolerance	T_{SJITOL}				UI	>8.5 Gbps – 12.7 Gbps ^{5, 10}

7.6.1 FPGA Programming Cycle and Retention

The following table describes FPGA programming cycle and retention.

Table 68 • FPGA Programming Cycles vs Retention Characteristics

Programming T _i	Programming Cycles, Max	Retention Years	Retention Years at T _i
0 °C to 85 °C	1000	20	85 °C
0 °C to 100 °C	500	20	100 °C
–20 °C to 100 °C	500	20	100 °C
–40 °C to 100 °C	500	20	100 °C
–40 °C to 85 °C	1000	16	100 °C
–40 °C to 55 °C	2000	12	100 °C

Note: Power supplied to the device must be valid during programming operations such as programming and verify . Programming recovery mode is available only for in-application programming mode and requires an external SPI flash.

7.6.2 FPGA Programming Time

The following tables describe FPGA programming time.

Table 69 • Master SPI Programming Time (IAP)

Parameter	Symbol	Devices	Typ	Max	Unit
Programming time	T _{PROG}	MPF100T, TL, TS, TLS			s
		MPF200T, TL, TS, TLS	17	25	s
		MPF300T, TL, TS, TLS	26	32	s
		MPF500T, TL, TS, TLS			s

Table 70 • Slave SPI Programming Time

Parameter	Symbol	Devices	Typ	Max	Unit
Programming time	T _{PROG}	MPF100T, TL, TS, TLS			s
		MPF200T, TL, TS, TLS	41 ¹		s
		MPF300T, TL, TS, TLS	50 ¹	60	s
		MPF500T, TL, TS, TLS			s

1. SmartFusion2 with MSS running at 100 MHz, MSS_SPI_0 port running at 6.67 MHz. Bitstream stored in DDR. DirectC version 4.1.

Table 71 • JTAG Programming Time

Parameter	Symbol	Devices	Typ	Max	Unit
Programming time	T _{PROG}	MPF100T, TL, TS, TLS			s
		MPF200T, TL, TS, TLS		56	s
		MPF300T, TL, TS, TLS ¹		95	s
		MPF500T, TL, TS, TLS			s

1. Programmer: FlashPro5 with TCK 10 MHz. PC Configuration: Intel i7 at 3.6 GHz, 32 GB RAM, Windows 10.

Parameter	Typ	Max	Unit	Conditions
Time to destroy data in non-volatile memory (non-recoverable) ^{1, 4}			ms	One iteration of scrubbing
Time to scrub the fabric data ¹			s	Full scrubbing
Time to scrub the pNVM data (like new) ^{1, 2}			s	Full scrubbing
Time to scrub the pNVM data (recoverable) ^{1, 3}			s	Full scrubbing
Time to scrub the fabric data pNVM data (non-recoverable) ¹			s	Full scrubbing
Time to verify ⁵			s	

1. Total completion time after entering zeroization.
2. Like new mode—zeroizes user design security setting and sNVM content.
3. Recoverable mode—zeroizes user design security setting, sNVM and factory keys.
4. Non-recoverable mode—zeroizes user design security setting, sNVM and factory keys, and factory data required for programming.
5. Time to verify after scrubbing completes.

7.6.7 Verify Time

The following tables describe verify time.

Table 81 • Standalone Fabric Verify Times

Parameter	Devices	Max	Unit
Standalone verification over JTAG	MPF100T, TL, TS, TLS		s
	MPF200T, TL, TS, TLS	53 ¹	s
	MPF300T, TL, TS, TLS	90 ¹	s
	MPF500T, TL, TS, TLS		s
Standalone verification over SPI	MPF100T, TL, TS, TLS		s
	MPF200T, TL, TS, TLS	37 ²	s
	MPF300T, TL, TS, TLS	55 ²	s
	MPF500T, TL, TS, TLS		s

1. Programmer: FlashPro5, TCK 10 MHz; PC configuration: Intel i7 at 3.6 GHz, 32 GB RAM, Windows 10.
2. SmartFusion2 with MSS running at 100 MHz, MSS_SPI_0 port running at 6.67 MHz. DirectC version 4.1.

Notes:

- Standalone verify is limited to 2,000 total device hours over the industrial –40 °C to 100 °C temperature.
- Use the digest system service, for verify device time more than 2,000 hours.
- Standalone verify checks the programming margin on both the P and N gates of the push-pull cell.
- Digest checks only the P side of the push-pull gate. However, the push-pull gates work in tandem. Digest check is recommended if users believe they will exceed the 2,000-hour verify time specification.

Table 82 • Verify Time by Programming Hardware

Devices	IAP	FlashPro4	FlashPro5	BP	Silicon Sculptor	Units
MPF100T, TL, TS, TLS						
MPF200T, TL, TS, TLS	9	67	53			s
MPF300T, TL, TS, TLS	14	95	90			s

Parameter	Symbol	Min	Typ	Max	Unit	Conditions
Authenticated text read		113.25	114.02	118.5	μs	
Authenticated and decrypted text read		159.59	160.53	166.5	μs	

Notes:

- Page size= 252 bytes (non-authenticated), 236 bytes (authenticated).
- Only page reads and writes allowed.
- T_{PUF_OVHD} is an additional time that occurs on the first R/W, after cold or warm boot, to sNVM using authenticated or authenticated and encrypted text.

7.6.10 Secure NVM Programming Cycles

The following table describes secure NVM programming cycles.

Table 86 • sNVM Programming Cycles vs. Retention Characteristics

Programming Temperature	Programming Cycles per Page, Max	Programming Cycles per Block, Max	Retention Years
–40 °C to 100 °C	10,000	100,000	20
–40 °C to 85 °C	10,000	100,000	20
–40 °C to 55 °C	10,000	100,000	20

Note: Page size = 128 bytes. Block size = 56 KBytes.

7.7 System Services

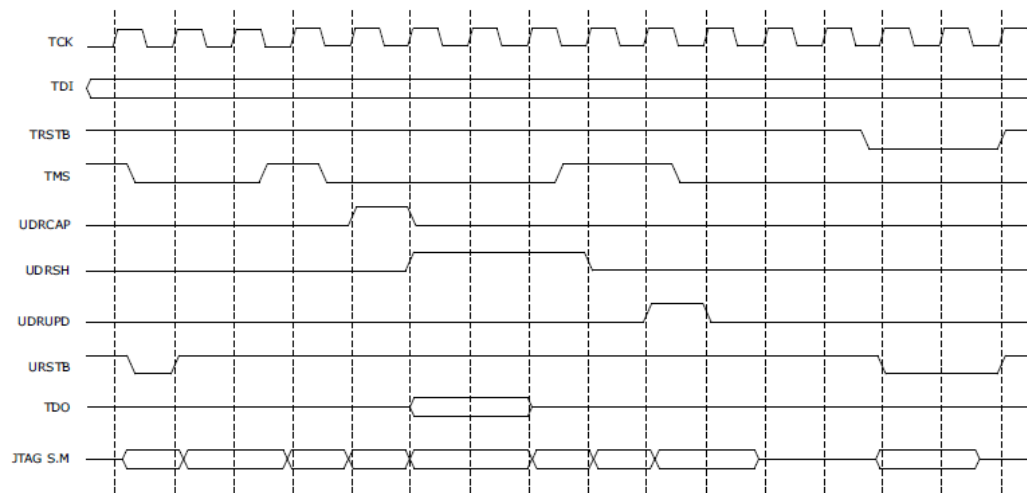
This section describes system switching and throughput characteristics.

7.7.1 System Services Throughput Characteristics

The following table describes system services throughput characteristics.

Table 87 • System Services Throughput Characteristics

Parameter	Symbol	Service ID	Typ	Max	Unit	Conditions
Serial number	T_{Serial}	00H	65	67	μs	
User code	T_{User}	01H	0.8	1.05	μs	
Design information	T_{Design}	02H	2.4	2.7	μs	
Device certificate	T_{Cert}	03H	255	271	ms	
Read digests	T_{digest_read}	04H	201	215	μs	
Query security locks	T_{sec_Query}	05H	15	17	μs	
Read debug information	T_{Rd_debug}	06H	34	38	μs	
Reserved		07H–0FH				
Secure NVM write plain text	$T_{SNVM_Wr_Plain}$	10H				Note 1
Secure NVM write authenticated plain text	$T_{SNVM_Wr_Auth}$	11H				Note 1
Secure NVM write authenticated cipher text	$T_{SNVM_Wr_Cipher}$	12H				Note 1
Reserved		13H–17H				

Figure 3 • UJTAG Timing Diagram

7.8.2 UJTAG_SEC Switching Characteristics

The following table describes characteristics of UJTAG_SEC switching.

Table 89 • UJTAG Security Performance Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
TCK frequency	F _{TCK}				MHz	

7.8.3 USPI Switching Characteristics

The following section describes characteristics of USPI switching.

Table 90 • SPI Macro Interface Timing Characteristics

Parameter	Symbol	V _{DDI} = 3.3 V Max	V _{DDI} = 2.5 V Max	V _{DDI} = 1.8 V Max	V _{DDI} = 1.5 V Max	V _{DDI} = 1.2 V Max	Unit
Propagation delay from the fabric to pins ¹	TPD_MOSI	0.8	1	1.2	1.4	1.6	ns
	TPD_MISO	3.5	3.75	4	4.25	4.5	ns
	TPD_SS	3.5	3.75	4	4.25	4.5	ns
	TPD_SCK	3.5	3.75	4	4.25	4.5	ns
	TPD_MOSI_OE	3.5	3.75	4	4.25	4.5	ns
	TPD_SS_OE	3.5	3.75	4	4.25	4.5	ns
	TPD_SCK_OE	3.5	3.75	4	4.25	4.5	ns

1. Assumes CL of the relevant I/O standard as described in the input and output delay measurement tables.

Parameter	Min	Typ	Max	Unit	Condition
Voltage sensing range	0.9		2.8	V	
Voltage sensing accuracy	–1.5		1.5	%	

Table 93 • Tamper Macro Timing Characteristics—Flags and Clearing

Parameter	Symbol	Typ	Max	Unit
From event detection to flag generation	T _{JTAG_ACTIVE} ^{1, 2}	45	52	ns
	T _{MESH_ERR} ²	1.8	2.2	μs
	T _{CLK_GLITCH} ^{1, 2}			ns
	T _{CLK_FREQ} ^{1, 2}			μs
	T _{LOW_1P05} ²	70	108	μs
	T _{HIGH_1P8} ²	85	120	μs
	T _{HIGH_2P5} ²	130	520	μs
	T _{GLITCH_1P05} ²			μs
	T _{SECDEC} ^{1, 2}			μs
	T _{DRI_ERR} ²	14	18	μs
	T _{WDOG} ^{1, 2}			μs
	T _{LOCK_ERR} ²			μs
Time from system controller instruction execution to flag generation	T _{INST_BUF_ACCESS} ^{2, 3}	4	5	μs
	T _{INST_DEBUG} ^{2, 3}	3.3	4	μs
	T _{INST_CHK_DIGEST} ^{2, 3}	1.8	3	μs
	T _{INST_EC_SETUP} ^{2, 3}	1.8	2	μs
	T _{INST_FACT_PRIV} ^{2, 3}	3.8	5	μs
	T _{INST_KEY_VAL} ^{2, 3}	2.5	3.1	μs
	T _{INST_MISC} ^{2, 3}	1.5	2	μs
	T _{INST_PASSCODE_MATCH} ^{2, 3}	2.5	3	μs
	T _{INST_PASSCODE_SETUP} ^{2, 3}	4.2	5	μs
	T _{INST_PROG} ^{2, 3}	3.8	4.1	μs
	T _{INST_PUB_INFO} ^{2, 3}	4	4.5	μs
	T _{INST_ZERO_RECO} ^{2, 3}	2.5	3	μs
	T _{INST_PASSCODE_FAIL} ^{2, 3}	170	180	μs
	T _{INST_KEY_VAL_FAIL} ^{2, 3}	92	110	μs
	T _{INST_UNUSED} ^{2, 3}	4	5	μs
Time from sending the CLEAR to deassertion on FLAG	T _{CLEAR_FLAG}	17	23	ns

1. Not available during Flash*Freeze.
2. The timing does not impact the user design, but it is useful for security analysis.
3. System service requests from the fabric will interrupt the system controller delaying the generation of the flag.

Table 94 • Tamper Macro Response Timing Characteristics

Parameter	Symbol	Typ	Max	Unit
Time from triggering the response to all I/Os disabled	T _{IO_DISABLE}	40	50	ns

Table 107 • SPI Master Mode (PolarFire Master) During Device Initialization

Parameter	Symbol	Min	Typ	Max	Unit	Condition
SCK frequency	F _{MSCK}			40	MHz	

Table 108 • SPI Slave Mode (PolarFire Slave)

Parameter	Symbol	Min	Typ	Max	Unit	Condition
SCK frequency	F _{SSCK}			80	MHz	

7.10.3 SmartDebug Probe Switching Characteristics

The following table describes characteristics of SmartDebug probe switching.

Table 109 • SmartDebug Probe Performance Characteristics

Parameter	Symbol	V _{DD} = 1.0 V STD	V _{DD} = 1.0 V – 1	V _{DD} = 1.05 V STD	V _{DD} = 1.05 V – 1	Unit
Maximum frequency of probe signal	F _{MAX}	100	100	100	100	MHz
Minimum delay of probe signal	T _{Min_delay}	13	12	13	12	ns
Maximum delay of probe signal	T _{Max_delay}	13	12	13	12	ns

7.10.4 DEVRST_N Switching Characteristics

The following table describes characteristics of DEVRST_N switching.

Table 110 • DEVRST_N Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
DEVRST_N ramp rate	DR _{RAMP}	10			μs	It must be a normal clean digital signal, with typical rise and fall times
DEVRST_N assert time	DR _{ASSERT}	1			μs	The minimum time for DEVRST_N assertion to be recognized
DEVRST_N de-assert time	DR _{DEASSERT}	2.75			ms	The minimum time DEVRST_N needs to be de-asserted before assertion

7.10.5 FF_EXIT Switching Characteristics

The following table describes characteristics of FF_EXIT switching.

Table 111 • FF_EXIT Electrical Characteristics

Parameter	Symbol	Min	Typ	Max	Unit	Condition
FF_EXIT_N ramp rate	FF _{RAMP}		10		μs	
Minimum FF_EXIT_N assert time	FF _{ASSERT}	1			μs	The minimum time for FF_EXIT_N to be recognized
Minimum FF_EXIT_N de-assert time	FF _{DEASSERT}	170			μs	The minimum time FF_EXIT_N needs to be de-asserted before assertion

ECDSA SigVer, P-384/SHA-384	1024	6421841	5759
	8K	6273510	5759
Key Agreement (KAS), P-384		5039125	6514
Point Multiply, P-256 ¹		5176923	4482
Point Multiply, P-384 ¹		12043199	5319
Point Multiply, P-521 ¹		26887187	6698
Point Addition, P-384		3018067	5779
KeyGen (PKG), P-384		12055368	6908
Point Verification, P-384		5091	3049

1. With DPA counter measures.

Table 120 • IFC (RSA)

Modes	Message Size (bits)	Athena TeraFire Crypto Core Clock-Cycles	CAL Delay In CPU Clock-Cycles
Encrypt, RSA-2048, e=65537	2048	436972	8,972
Encrypt, RSA-3072, e=65537	3072	962162	12,583
Decrypt, RSA-2048 ¹ , CRT	2048	26862392	15900
Decrypt, RSA-3072 ¹ , CRT	3072	75153782	22015
Decrypt, RSA-4096, CRT	4096	89235615	23710
Decrypt, RSA-3072, CRT	3072	37880180	18638
SigGen, RSA-3072/SHA-384 ¹ , CRT, PKCS #1 V 1.1.5	1024	75197644	20032
	8K	75213653	19303
SigGen, RSA-3072/SHA-384, PKCS #1, V 1.5	1024	148090970	14642
	8K	148102576	13936
SigVer, RSA-3072/SHA-384, e = 65537, PKCS #1 V 1.5	1024	970991	12000
	8K	982011	11769
SigVer, RSA-2048/SHA-256, e = 65537, PKCS #1 V 1.5	1024	443493	8436
	8K	453007	8436
SigGen, RSA-3072/SHA-384, ANSI X9.31	1024	147138254	13945
	8K	147155896	13523
SigVer, RSA-3072/SHA-384, e = 65537, ANSI X9.31	1024	973269	11313
	8K	983255	11146

1. With DPA counter measures.

Table 121 • FFC (DH)

Modes	Message Size (bits)	Athena TeraFire Crypto Core Clock-Cycles	CAL Delay In CPU Clock-Cycles
SigGen, DSA-3072/SHA-384 ¹	1024	27932907	13969
	8K	27942415	13501
SigGen, DSA-3072/SHA-384	1024	12086356	13602
SigVer, DSA-3072/SHA-384	1024	24597916	15662
	8K	24229420	15133